



Radiation Hard Pixel Sensors for the Phase 2 Upgrade of the CMS Inner Tracker

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on behalf of the Tracker Group of the CMS Collaboration

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The CMS Inner Tracker (IT) for Phase 2

HL-LHC [1] upgrade to greatly expand the physics reach of the experiments

- Instantaneous luminosity increased up to 7.5E34 cm⁻²s⁻¹
 - Reduced pixel size by x6 to $25 \times 100 \ \mu m^2$ to maintain occupancy $< 10^{-4}$ at L1
- Integrated luminosity increased by x10 to 3000-4000 fb⁻¹
 - Radiation hard planar sensors, 3D sensors in innermost barrel layer

CMS Inner Tracker (IT) with extended coverage to $|\eta| \simeq 4.0$ for HL-LHC discovery and precision physics[2]







Radiation Effects

Severe radiation effects during HL-LHC running

- Sensors: Higher operation voltages, smaller signal, large leakage currents \rightarrow cooling critical
- Total Ionizing Dose (TID) effects readout chip performance
- TBPX layer 1 and TFPX ring 1 foreseen to be replaced during HL-LHC





CMS IT Readout Chip

CROC frontend chip in 65 nm CMOS developped by RD53 [1]

- Radiation hard to 1 Grad
- Power < 1 W/cm²
- Serial powering via shunt-LDO regulators
- CMS: Linear analog front-end [2,3] with Krummenacher feedback
 - Can cope with large detector leakage currents
- Low, adjustable threshold: 1000 e vs. 2000 e of current chip
 - Sensor thickness 285 μ m (current detector) \rightarrow 150 μ m (upgrade)
- 4 bit digital readout with time-over-threshold counter (ToT)





Single chip PCB for testing

RD53B user guide.
2021 JINST 16 P12014.
CERN-RD53-PUB-20-002.

Planar Sensor Modules for CMS IT

Only two types of hybrid planar bare sensor modules: 2x2 and 1x2 CROC

- Logistics and management of spares easier
- However, full modules (flex prints) in TBPX, TFPX, TEPX differ
- 150 μm thick n⁺p sensors, signal (MPV) 11 ke for a MIP

TEPX module



Large pixels in inter-chip regions: no dead regions





6 2x2 sensors per 150 mm wafer or 12 1x2 sensors (not shown)

[1] Evaluation of Planar Silicon Pixel Sensors with the RD53A Readout Chip for the Phase-2 Upgrade of the CMS Inner Tracker <u>(arXiv:2307.01580)</u>.

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Selected Sensor Specifications

	Planar	3D	
active thickness, polarity	150 μm, n⁺p, pstop	150 μm, n⁺p, pspray	
depletion voltage, V _{fd}	< 100 V	< 10 V	
breakdown voltage	> 350 V	> V _{fd} +35 V	
leakage current (before irradiation)	< 0.75 µA cm ⁻² at V _{fd} +50 V, 20 °C	< 2.5 µA cm ⁻² at V _{fd} + 25 V, 20 °C	
leakage current after $\Phi_{\rm eq}$ = 5E15 cm ⁻² *	< 45 µA cm ⁻² at 600 V, -25°C		
leakage current after $\Phi_{\rm eq}$ = 1.5E16 cm $^{-2}$		< 100 µA/cm ² at V _{op} (<200 V), -25°C	
hit efficiency (before irradiation)	99 %	96 (97) % at 0°(10°) angle)
hit efficiency for Φ_{eq} = 5E15 cm ⁻² hit efficiency for Φ_{eq} = 1E16 cm ⁻² hit efficiency for Φ_{eq} = 1.5E16 cm ⁻²	99 % 98 %	96 (97) % at 0°(10°) angle	

*Annealing at 60°C for 1 hr

V_{op}: operation voltage



Planar Sensors + CROC

- HPK-CROC single chip assemblies irradiated up to Φ_{eq} = 1E16 cm⁻² at CERN PS (23 GeV p)
- Excellent performance:
 - ϵ > 98%, taking noisy pixels into account
 - Noisy pixel < 1%





Performance: Hit Efficiency vs. Thresh.

Planar Sensors + CROC

- HPK-CROC single chip assemblies irradiated up to Φ_{eq} = 1E16 cm⁻² at CERN PS (23 GeV p)
- Threshold < 1500 e required at 600 V for ϵ > 98% for Φ_{eq} > 5E15 cm⁻²
- Stronger degradation at 9.5° angle due to charge sharing (backup)



stronger degradation at 400 V:

Performance: Spatial Resolution

Spatial resolution determined in DESY II testbeam [1]

- Electron energies 1-6 GeV, here: 5.2 GeV
- Prototype sensor-**RD53A** modules, final pixel cell
- Measured width of residual distribution corrected for track resolution
- Resolution 2 μm at optimal angle

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• Degradation with irradiation, but always better than the "binary" resolution $pitch/\sqrt{12}$





Cross Talk in Planar Sensors

25 x 100 μm^2 sensor pixels matched to 50 x 50 μm^2 in FE chip

• Overlap of metal and neighbor implant \rightarrow cross talk, XT

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- Depends on fine tuning of readout timing vs. signal injection
- 4% to 6% for coupled, 2.4% to 2.8% for uncoupled pixels
- Independent of timing and much larger in assemblies with first prototype chip RD53A



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Validation of a Full Module

- TBPX 2x2 module in FNAL testbeam
- Excellent performance confirmed

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- Larger cells in inter-CROC regions
- Below: Two columns of 225 x 25 μ m²
 - Residuals as expected
- Efficiency of special cells > 99 %
- Analysis of irrad. 2x2 module under way







Why 3D: Thermal Simulations

3D sensors in layer 1, Φ_{eq} = 1.5E16 cm⁻²

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planar sensors in layer 2, Φ_{eq} = 1E16⁻² cm⁻²



- 3D sensors only solution for layer 1 for Φ_{eq} = 1.5E16 cm⁻²
- Thermal performance of 3D sensors good enough to select lighter design for cooling plate and mechanics
- Planar sensors have sufficient margin in all other layers for fluences $\Phi_{\rm eq}$ < 1E16 cm⁻² 12

CMS 3D Sensors



• 150 mm Si-Si wafers

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- 150 μm active thickness, p-spray isolation
- Support wafer thinned to 100 μ m at hybridization vendor
- $25x100 \ \mu m^2$ pixel cell with 1 electrode at the center
- Single-CROC size for higher production yield
 - Module contain two sensors



[1] Results on proton-irradiated 3D pixel sensors interconnected to RD53A readout ASIC (NIMA, Vol. 944, 2019, 162625).

Validation of 3D Assemblies

• Modules tuned to 1000 e threshold at -30°C

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- Operation range from full ε to onset of noise: 90 V \rightarrow 130 V (CNM) and \rightarrow 150 V (FBK)
- Noisy and "stuck" pixels masked Noisy = occupancy >2x10⁻⁵





Production

Module production

- Follows CROC and sensor production, flip chip
- 12 production and test centers: Europe/US
- Max throughput 300 modules per month

optical inspection Sensor IV curves (*) production Flip Chip optical inspection bare module tests bump only on demand bonding extensive QC incl. Module cold cycle tests production



(*) no bias grid for planar sensor , only guard ring IV plus IV on test sensors



Summary and Outlook

- Entirely new CMS Tracker for HL-LHC for optimal physics reach in challenging condition
- Inner Tracker: Hybrid pixel detector modules with pixel sizes of 25 μm x 100 μm
- Planar sensors with 150 μm active thickness, innermost TBPX layer: 3D sensors
- Excellent performance of prototype modules: hit efficiency, spatial resolution, radiation hardness
- Planar sensor modules qualified to $\Phi_{eq} > 1 \times 10^{16} \text{ cm}^{-2}$
- 3D sensors modules qualified to $\Phi_{\rm eq}$ > 1.5 x 10¹⁶ cm⁻²

Towards production

- First orders for (pre)production planar and 3D sensors have been placed
- Module production driven by CROC_v2 FE chip will start Q3/2024 and last 2.5 years

See also talks on "TID effects study on the monitoring system of the RD53 chip" by Mohsine Menouni and "Prototype validation for the CMS Inner Tracker Phase-2 upgrade" by Nazar Bartosik



Backup

Planar Sensor Wafer Layouts



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Modules



Installed	ТВРХ	TFPX	TEPX	Total
1x2	324	832	0	1156
2x2	432	896	1408	2736
Total	756	1728	1408	3892



	RUN 4 (800 fb ⁻¹)		RUN 5 (1300 fb ⁻¹	RUN 4+5 (2100 fb ⁻¹)		5 ⁻¹)	RUN 4+5+6 (3000 fb ⁻¹)		Not in Chamonix 2022 (4000 fb ⁻¹) For reference only	
	1E16 1 MeV neq	Grad	1E16 1 MeV neq	Grad	1E16 1 MeV neq	Grad	1E16 1 MeV neq	Grad	1E16 1 MeV neq	Grad
TBPX L1	0.69	0.36	1.12	0.58	1.81	0.93	2.58	1.34	3.44	1.78
TBPX L2	0.18	0.11	0.29	0.17	0.48	0.28	0.68	0.40	0.98	0.54
TFPX R1	0.46	0.31	0.75	0.49	1.22	0.79	1.74	1.13	2.32	1.5
TFPX R2	0.21	0.14	0.35	0.23	0.57	0.37	0.82	0.53	1.09	0.71

• tkLayout

https://cms-tklayout.web.cern.ch/cms-tklayout/layouts/recent-layouts/OT801_IT701/irradiation_Pixels.html

Chamonix 2002 luminosity profile

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Performance: Hit Efficiency @9.5° DER FORSCHUNG | DER LEHRE | DER BILDUNG

Planar Sensors + CROC

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- HPK-CROC single chip assemblies irradiated up to Φ_{eq} = 1E16 cm⁻² at CERN PS (23 GeV p)
- Excellent performance:
 - ϵ > 98%, taking noisy pixels into account
 - Noisy pixel < 1%





fluence gradient: Selected ROIs with different fluences on the same module



Performance: Hit Efficiency vs. Thresh.

Planar Sensors + CROC @ 9.5°

- HPK-CROC single chip assemblies irradiated up to Φ_{eq} = 1E16 cm⁻² at CERN PS (23 GeV p)
- Threshold < 1500 e required at 600 V for ε > 98% for Φ_{eq} > 5E15 cm⁻², much stronger degradation at 9.5° due to charge sharing





hit efficiency, not corrected for acceptance









Planar Sensors + CROC

- HPK-CROC single chip assemblies irradiated to Φ_{eq} = 1E16 cm⁻² at CERN PS (23 GeV p)
- Excellent performance:
 - ϵ > 98%, taking noisy pixels into account
 - Noisy pixel < 1 %</p>







Bias scan: efficiency vs. Vbias



100

99

97 96.5 96

95.5 95 94.5

94 93.5 93

92.5

91.5

90.5

92

91

98.5 98 97.5

Efficiency [%] 99.5

Planar Sensors + CROC

- HPK-CROC single chip assemblies irradiated to Φ_{eq} = 1E16 cm⁻² at CERN PS (23 GeV p)
- Excellent performance: ٠
 - ϵ > 98%, taking noisy pixels into account
 - Noisy pixel < 1%
- Consistent results for CROC and RD53A* modules:



Bias scan: efficiency vs. Vbias

.

700 Bias voltage [V]

25

700

Bias voltage [V]

650

02-21: efficiency*accentance

HPK 03-21: efficiency

CROC HPK 03-21: efficiency*acceptance



Thermal simulations: 3D

Last simulations – Plot with 70 uA/cm2 (140 V) for two different conditions of the cooling plate



Thermal simulations: 3D



Cooling plate with 5 windows – From 70 uA/cm² to 150 uA/cm² (140 V) the margin for thermal runaway is reduced by around 8°C. We can expect the same reduction for 1 window configuration (simulations are running).

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L1 sensor technology: 3D Sensor Qualification

Recent results beyond 1E16

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- FBK 100x25 3D sensors irrad. at KIT
- 23 MeV: High dose: 2-2.5 Grad
- Measured at CERN and DESY testbeam
- 1.4E16
 - ε: 99% at 130V
 - Noise(*) <1% up to 140 V
- 1.8E16
 - ε: 98% at 170V
 - Large increase of noisy pixels for V_{bias}> 140 V

* Noisy pixels defined with a cut at $2x10^{\text{-5}}$ on occupancy, corresponding to 1% of the L1 occupancy

